ELSEVIER

Thin Solid Films 319 (1998) 219

thin solid films

Author Index of Volume 319

Aggelakeris, M. 140
Andreazza, P. 62
Andreazza-Vignolle, C. 62
Andrew, N.L. 1
Angot, T. 168
Ardhuin, H. 157
Auzary, S. 163

Babonneau, D. 81
Balerna, A. 20
Barna, A. 115
Barna, P.B. 115
Barucca, G. 207
Béré, A. 153
Bessière, M. 191
Bischoff, J.L. 168
Boher, P. 67
Bonarski, J.T. 16, 39
Böni, P. 73
Braisaz, T. 140
Brecht, E. 202, 215
Breitmeier, U. 73

Cadeville, M.C. 191
Casanove, M.J. 157
Chelly, R. 168
Cheng, X.J. 29
Ciach, R. 16, 39
Clemens, D. 73
Comin, F. 20
Contour, J.-P. 211

Dauger, A. 197
De Barros, M.I. 62
De Benedittis, A. 207
De Caro, L. 49
Declemy, A. 44
Denanot, M.F. 163
Dentel, D. 168
De Padova, P. 20
Deville, J.P. 168
Di Cristoforo, A. 207
Donnet, C. 97
Drouet, M. 211
Durand, O. 211

Ehret, G. 168

Fadeyev, S.V. 84
Felici, R. 20
Ferrari, L. 20
Fert, A. 120
Fettar, F. 120
Fewster, P.F. 1
Flevaris, N. 140
Fodchuk, I.M. 39
Formoso, V. 20
Fruginskii, M.S. 84
Furuya, K. 101, 110

Gaboriaud, R.J. 163, 177
Garem, H. 177
Gartstein, E. 182
Geerk, J. 215
Gergaud, P. 9, 78
Girard, J.C. 44
Gladyszewski, G. 44, 78
Gorley, P. 39
Grill, A. 97
Grimmer, H. 73
Guerin, P. 44
Guinebretière, R. 197
Gust, W. 124

Haase, M. 25
Hairie, A. 153
Hashimoto, M. 115, 128
Hennet, L. 67
Hesse, D. 187
Heuken, M. 57
Honda, T. 110
Hong, M.H. 132
Horisberger, M. 73
Hÿtch, M.J. 157

Ichinose, H. 87
Igarashi, Y. 124

Jaouen, C. 44

Kalisch, H. 57
Karakostas, Th. 140
Kato, T. 92, 132
Kehagias, Th. 140
Kilaas, R. 157
Klimovskaya, A.I. 84
Komninou, Ph. 140
Kräußlich, J. 187
Kuroda, K. 92, 106, 132
Kuznicki, Z.T. 16, 39

Labat, S. 9, 78
Lach, S. 182
Lakner, H. 57
Langer, J. 187
Larciprete, R. 20
Leccabue, F. 207
Lefakis, H. 144
Lefebvre, S. 191
Linker, G. 202, 215
Lioutas, Ch.B. 144
Liu, Q. 25, 57
Logothetidis, S. 144
Luttmann, M. 67

Majni, G. 207
Makihara, K. 115
Maret, M. 191
Martin, J.M. 97
Mathé, E.L. 177
Mattheis, R. 187
Maurice, J.-L. 120, 211
Mengucci, P. 207
Mertins, H.-C. 73
Meyer, O. 215
Mogilyanski, D. 182
Monna, R. 177
Muller, J.C. 177

Nakai, H. 115, 128
Nakanose, M. 87
Naudon, A. 81
Noguchi, K. 128
Nouet, G. 140, 153
Nunome, K. 132

Ohashi, H. 128
Ortega, L. 20
Ostrovskii, I.P. 84

Pailloux, F. 163, 177
Patel, V. 97
Paumier, E. 153
Petroff, F. 81, 120
Ponsonnet, L. 97
Poulopoulos, P. 140
Prost, W. 25

Raransky, M.D. 39
Rats, D. 62
Reiner, J. 202
Rocher, A. 157, 172
Rodewald, M. 202
Romeo, M. 168
Rudyi, I.O. 84
Ruterana, P. 140, 153

Sacchetti, A. 49
Saito, T. 101
Saka, H. 92, 106, 132
Sasaki, K. 132
Schäfers, F. 73
Schelp, L.F. 120
Schneider, R. 215
Schuhrke, Th. 187
Sciacovelli, P. 49
Senz, St.. 187
Serra, A. 140
Snoeck, E. 157, 172
Soulestin, B. 197
Staiger, W. 191
Stehle, J.L. 67
Straumal, B.B. 124
Swiatek, Z. 16, 39

Takahashi, M. 92
Takeguchi, M. 110
Tanaka, M. 101, 110
Tapfer, L. 49
Tegude, F.J. 25
Thomas, O. 9, 78
Trætholt, C. 215
Tsuji, S. 92, 106
Tsujimoto, K. 106

Uhlaq-Bouillet, C. 168
Ulhaq-Bouillet, C. 191

Vandenbulcke, L. 62
Van Dyck, D. 148
Varlot, K. 97
Vaurès, A. 81, 120
Velling, P. 25
Vermaut, P. 153
Vershinin, N.F. 124
Vouroutzis, N. 144

Warot, B. 157
Watanabe, T. 124
Watts, B.E. 207
Werckmann, J. 168
Woitok, J. 57

Xu, J. 29, 57

Yang, J. 115

Zhao, X. 124
Zhuang, Y. 49
Zolotoyabko, E. 35
Zweck, J. 187

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ELSEVIER

Thin Solid Films 319 (1998) 220–223

thin solid films

Subject Index of Volume 319

Absolute strain level
Strain analysis by X-ray diffraction, 1
Ag/Fe multilayers
Ion-assisted deposition of Ag(001)/Fe(001) multilayers: interface roughness, 44
Alloy lattice
Combined high resolution X-ray diffraction and EXAFS studies of $Si_{(1-x)}Ge_x$ heterostructures, 20
AlN
The volume expansion of the $\{11\bar{2}0\}$ planar defect in 2H–GaN/6H–SiC $(0001)_{Si}$ grown by MBE, 153
Aluminum electrode
Electrode-width dependence of resistivity and structure of aluminum electrode thin film electron beam evaporated on lithium tantalate, 128
Amorphous alumina
TEM observations of nanometer thick cobalt deposits in alumina sandwiches, 120
Amorphous carbon film
Transmission electron microscopy investigation of the structural characteristics of amorphous tetrahedral carbon films, 144
Assumed lattice parameters
Strain analysis by X-ray diffraction, 1
Atomic structure
Atomic and electronic structure of diamond grain boundaries analyzed by HRTEM and EELS, 87
Atomistic calculation
The volume expansion of the $\{11\bar{2}0\}$ planar defect in 2H–GaN/6H–SiC $(0001)_{Si}$ grown by MBE, 153
Au/Ni multilayers
Structure characterization of metallic multilayers by symmetric and asymmetric X-ray diffraction, 78

Back-reflection technique
New X-ray diffraction method for materials science, 16
Barrier
HR XRD for the analysis of ultrathin centrosymmetric strained DB-RTD heterostructures, 25
$Bi_2Sr_2CaCu_2O_{8+\delta}$ thin films
Structural properties of $Bi_2Sr_2CaCu_2O_{8+\delta}$ thin films on (110) oriented $SrTiO_3$ substrates, 215
Brewster angle
X-ray reflectivity of multilayer mirrors for the water window, 73

Carbon
EELS analysis of hydrogenated diamond-like carbon films, 97
Co
Stable and metastable phases in the vacuum arc deposited Co thin films, 124
Cobalt
Morphological study of cobalt aggregates in magnetic multilayers by grazing-incidence small-angle X-ray scattering, 81
Cobalt clusters
TEM observations of nanometer thick cobalt deposits in alumina sandwiches, 120
Co_xPt_{1-x} alloy films
Investigation of chemical ordering in MBE-grown Co_xPt_{1-x} films by X-ray diffraction and high-resolution transmission electron microscopy, 191
Compositional distribution
HRXRD study of compositional uniformity of MOVPE grown InGaAs, 29
Composition variation
Study of structural properties of MOVPE grown ZnMgSSe layer by HRXRD and cathodoluminescence, 57
Crystalline structures
Studies of metamorphic III–V heterostructures by digital processing of HREM images, 172
Crystallisation
Crystallisation of perovskite PZT films on MgO substrates, 207
Crystallite group method
Limits of validity of the crystallite group method in stress determination of thin film structures, 9

d.c.-Biased plasma-sputter-deposition
Growth structure of nickel films on GaAs(001) by d.c.-biased plasma-sputter-deposition, 115
Deposition
Surface observation of Mo nanocrystals deposited on Si (111) thin films by a newly developed ultrahigh vacuum field-emission transmission electron microscope, 110
Transmission electron microscopy investigation of the structural characteristics of amorphous tetrahedral carbon films, 144
Diamond
In-depth structural X-ray investigation of PECVD grown diamond films on titanium alloys, 62
Diamond film
Application of focused ion beam milling to cross-sectional TEM specimen preparation of industrial materials including heterointerfaces, 92
Diamond-like carbon films
EELS analysis of hydrogenated diamond-like carbon films, 97
Diamond polycrystalline film
Atomic and electronic structure of diamond grain boundaries analyzed by HRTEM and EELS, 87
Dilatation
Lattice parameter change in submicron Si whiskers, 84
Dislocations
Microstructure and strain relaxation in $YBa_2Cu_3O_7$ epitaxial thin films, 211
Displacement
Quantitative analysis of strain field in thin films from HRTEM micrographs, 157

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PII S0040-6090(97)01125-5

Double-barrier resonant tunnelling diodes
HR XRD for the analysis of ultrathin centrosymmetric strained DB-RTD heterostructures, 25

Electron
HREM: ultimate performances, 148
Electron-energy loss spectroscopy
EELS analysis of hydrogenated diamond-like carbon films, 97
Electronic structure
Atomic and electronic structure of diamond grain boundaries analyzed by HRTEM and EELS, 87
Epitaxial film
XRD and TEM study of heteroepitaxial growth of zirconia on magnesia single crystal, 197
Epitaxial growth
Epitaxial growth of $YBa_2Cu_3O_{7-x}$ thin films on (111) $SrTiO_3$ substrates, 202
Epitaxial thin films
Microstructure and strain relaxation in $YBa_2Cu_3O_7$ epitaxial thin films, 211
EXAFS analysis
Combined high resolution X-ray diffraction and EXAFS studies of $Si_{(1-x)}Ge_x$ heterostructures, 20

Focused ion beam
Transmission electron microscopy of thin-film transistors on glass substrates, 106
Cross-sectional TEM observation of multilayer structure of a galvannealed steel, 132
Focused ion beam (FIB)
Application of focused ion beam milling to cross-sectional TEM specimen preparation of industrial materials including heterointerfaces, 92
Focused ion beam irradiation
TEM observation of structural differences between two types of Ni silicide/Si thin films caused by FIB irradiation, 101
Fourier analysis
Microstructure imaging of the YBCO thin film/MgO substrate interface: HRTEM and Fourier analysis of the Moiré fringe pattern, 163

GaAs substrate
Growth structure of nickel films on GaAs(001) by d.c.-biased plasma-sputter-deposition, 115
Gallium nitrides
The volume expansion of the $\{11\bar{2}0\}$ planar defect in 2H–GaN/6H–SiC $(0001)_{Si}$ grown by MBE, 153
Galvanized steel
Application of focused ion beam milling to cross-sectional TEM specimen preparation of industrial materials including heterointerfaces, 92
GaN
The volume expansion of the $\{11\bar{2}0\}$ planar defect in 2H–GaN/6H–SiC $(0001)_{Si}$ grown by MBE, 153
GaSb/GaAs interface
Quantitative analysis of strain field in thin films from HRTEM micrographs, 157
Ge coordination ratio
Combined high resolution X-ray diffraction and EXAFS studies of $Si_{(1-x)}Ge_x$ heterostructures, 20
GIXD
In-depth structural X-ray investigation of PECVD grown diamond films on titanium alloys, 62
Glass substrates
Transmission electron microscopy of thin-film transistors on glass substrates, 106
Grain structure
Stable and metastable phases in the vacuum arc deposited Co thin films, 124
Graphite
EELS analysis of hydrogenated diamond-like carbon films, 97
Grazing X-ray reflectance
Combined characterization of conductive materials by infrared spectroscopic ellipsometry and grazing X-ray reflectance, 67

High-resolution electron microscopy
Nanocrystalline thin titanium films grown on potassium bromide single crystals, 140
High resolution electron microscopy
The volume expansion of the $\{11\bar{2}0\}$ planar defect in 2H–GaN/6H–SiC $(0001)_{Si}$ grown by MBE, 153
High-resolution transmission electron microscopy
HRTEM study of strained Si/Ge multilayers, 168
Investigation of chemical ordering in MBE-grown Co_xPt_{1-x} films by X-ray diffraction and high-resolution transmission electron microscopy, 191
Holographic
HREM: ultimate performances, 148
HREM
Quantitative analysis of strain field in thin films from HRTEM micrographs, 157
HRTEM
Microstructure imaging of the YBCO thin film/MgO substrate interface: HRTEM and Fourier analysis of the Moiré fringe pattern, 163
Hurst parameter
Determination of interfacial roughness and its correlation in sputtered CoZr/Cu multilayers, 187

Image treatment
HRTEM study of strained Si/Ge multilayers, 168
Infrared spectroscopic ellipsometry
Combined characterization of conductive materials by infrared spectroscopic ellipsometry and grazing X-ray reflectance, 67
Inhomogeneous structures
Investigation of inhomogeneous structures of near-surface-layers in ion-implanted silicon, 39
Interface effects
Fine interference effects in X-ray diffraction from multilayered structures, 35
Interface roughness
Ion-assisted deposition of Ag(001)/Fe(001) multilayers: interface roughness, 44
Interfacial roughness
Determination of interfacial roughness and its correlation in sputtered CoZr/Cu multilayers, 187
Ion-assisted deposition
Ion-assisted deposition of Ag(001)/Fe(001) multilayers: interface roughness, 44
Ion-implanted silicon
Investigation of inhomogeneous structures of near-surface-layers in ion-implanted silicon, 39
Irradiation
Surface observation of Mo nanocrystals deposited on Si (111) thin films by a newly developed ultrahigh vacuum field-emission transmission electron microscope, 110

Lamellae
Optical and digital processing of H.R.T.E.M. images of Si thin films deposited by R.T.C.V.D., 177
Lattice parameter
Lattice parameter change in submicron Si whiskers, 84
Lead zirconate titanate films
Crystallisation of perovskite PZT films on MgO substrates, 207

Linear polarizers
X-ray reflectivity of multilayer mirrors for the water window, 73
Lithium tantalate
Electrode-width dependence of resistivity and structure of aluminum electrode thin film electron beam evaporated on lithium tantalate, 128

Magnetic multilayers
Morphological study of cobalt aggregates in magnetic multilayers by grazing-incidence small-angle X-ray scattering, 81
Materials science
New X-ray diffraction method for materials science, 16
Matrix
Optical and digital processing of H.R.T.E.M. images of Si thin films deposited by R.T.C.V.D., 177
MBE
The volume expansion of the $\{11\bar{2}0\}$ planar defect in 2H–GaN/6H–SiC $(0001)_{Si}$ grown by MBE, 153
MgO
XRD and TEM study of heteroepitaxial growth of zirconia on magnesia single crystal, 197
MgO substrate
Microstructure imaging of the YBCO thin film/MgO substrate interface: HRTEM and Fourier analysis of the Moiré fringe pattern, 163
MgO substrates
Crystallisation of perovskite PZT films on MgO substrates, 207
Microelectronics
Combined characterization of conductive materials by infrared spectroscopic ellipsometry and grazing X-ray reflectance, 67
Microparticles
Stable and metastable phases in the vacuum arc deposited Co thin films, 124
Microstructure
In-depth structural X-ray investigation of PECVD grown diamond films on titanium alloys, 62
Microstructure and strain relaxation in $YBa_2Cu_3O_7$ epitaxial thin films, 211
Microtwins
Structural aspects of the interface in Silicon-on-sapphire system, 182
Misfit dislocation network
Studies of metamorphic III–V heterostructures by digital processing of HREM images, 172
Model of chain reaction
HRXRD study of compositional uniformity of MOVPE grown InGaAs, 29
Molecular beam epitaxy
The volume expansion of the $\{11\bar{2}0\}$ planar defect in 2H–GaN/6H–SiC $(0001)_{Si}$ grown by MBE, 153
MOVPE
HRXRD study of compositional uniformity of MOVPE grown InGaAs, 29
MOVPE grown ZnMgSSe
Study of structural properties of MOVPE grown ZnMgSSe layer by HRXRD and cathodoluminescence, 57
Multilayered structures
Fine interference effects in X-ray diffraction from multilayered structures, 35
Multilayers
HRTEM study of strained Si/Ge multilayers, 168
Determination of interfacial roughness and its correlation in sputtered CoZr/Cu multilayers, 187

Nanocrystalline film
Nanocrystalline thin titanium films grown on potassium bromide single crystals, 140
Nanocrystals
Surface observation of Mo nanocrystals deposited on Si (111) thin films by a newly developed ultrahigh vacuum field-emission transmission electron microscope, 110
Nanostructures
X-ray scattering study of quantum wires and lateral periodic heterostructures, 49
Near-surface-layers
Investigation of inhomogeneous structures of near-surface-layers in ion-implanted silicon, 39
Ni film
Growth structure of nickel films on GaAs(001) by d.c.-biased plasma-sputter-deposition, 115

Particle
HREM: ultimate performances, 148
PECVD
In-depth structural X-ray investigation of PECVD grown diamond films on titanium alloys, 62
Polycrystalline
Growth structure of nickel films on GaAs(001) by d.c.-biased plasma-sputter-deposition, 115
Precision determination of relaxation
Strain analysis by X-ray diffraction, 1

Reflectance peaks
X-ray reflectivity of multilayer mirrors for the water window, 73
Relaxation
HRTEM study of strained Si/Ge multilayers, 168
Relaxation and composition determination
Strain analysis by X-ray diffraction, 1
Relaxation process
Studies of metamorphic III–V heterostructures by digital processing of HREM images, 172
Resistivity
Electrode-width dependence of resistivity and structure of aluminum electrode thin film electron beam evaporated on lithium tantalate, 128
Rocking curve
HR XRD for the analysis of ultrathin centrosymmetric strained DB-RTD heterostructures, 25
Root mean square
Determination of interfacial roughness and its correlation in sputtered CoZr/Cu multilayers, 187
R.T.C.V.D.
Optical and digital processing of H.R.T.E.M. images of Si thin films deposited by R.T.C.V.D., 177

Sapphire
Structural aspects of the interface in Silicon-on-sapphire system, 182
SiC
The volume expansion of the $\{11\bar{2}0\}$ planar defect in 2H–GaN/6H–SiC $(0001)_{Si}$ grown by MBE, 153
SiGe
HRTEM study of strained Si/Ge multilayers, 168
Silicon
Structural aspects of the interface in Silicon-on-sapphire system, 182
Si whiskers
Lattice parameter change in submicron Si whiskers, 84
Small-angle X-ray scattering technique under grazing incidence (GISAXS)
Morphological study of cobalt aggregates in magnetic multilayers by grazing-incidence small-angle X-ray scattering, 81
Sol–gel
XRD and TEM study of heteroepitaxial growth of zirconia on magnesia single crystal, 197
$SrTiO_3$ substrates
Epitaxial growth of $YBa_2Cu_3O_{7-x}$ thin films on (111) $SrTiO_3$ substrates, 202

Structural properties of $Bi_2Sr_2CaCu_2O_{8+\delta}$ thin films on (110) oriented $SrTiO_3$ substrates, 215
Stacking fault
The volume expansion of the $\{11\bar{2}0\}$ planar defect in 2H–GaN/6H–SiC $(0001)_{Si}$ grown by MBE, 153
Steel
Cross-sectional TEM observation of multilayer structure of a galvannealed steel, 132
Strain
Quantitative analysis of strain field in thin films from HRTEM micrographs, 157
HRTEM study of strained Si/Ge multilayers, 168
Strain relaxation
Microstructure and strain relaxation in $YBa_2Cu_3O_7$ epitaxial thin films, 211
Stress determination
Limits of validity of the crystallite group method in stress determination of thin film structures, 9
Structural properties
Structural properties of $Bi_2Sr_2CaCu_2O_{8+\delta}$ thin films on (110) oriented $SrTiO_3$ substrates, 215
Structure characterization
Structure characterization of metallic multilayers by symmetric and asymmetric X-ray diffraction, 78
Substrate
TEM observation of structural differences between two types of Ni silicide/Si thin films caused by FIB irradiation, 101
Surface analysis
Surface observation of Mo nanocrystals deposited on Si (111) thin films by a newly developed ultrahigh vacuum field-emission transmission electron microscope, 110
Surface morphology
X-ray scattering study of quantum wires and lateral periodic heterostructures, 49
Surface observation
Surface observation of Mo nanocrystals deposited on Si (111) thin films by a newly developed ultrahigh vacuum field-emission transmission electron microscope, 110

TEM
TEM observation of structural differences between two types of Ni silicide/Si thin films caused by FIB irradiation, 101
Thin film structures
Limits of validity of the crystallite group method in stress determination of thin film structures, 9
Thin-film transistor (TFT)
Application of focused ion beam milling to cross-sectional TEM specimen preparation of industrial materials including heterointerfaces, 92
Titanium
In-depth structural X-ray investigation of PECVD grown diamond films on titanium alloys, 62
Nanocrystalline thin titanium films grown on potassium bromide single crystals, 140
Transition zone
Studies of metamorphic III–V heterostructures by digital processing of HREM images, 172
Transmission electron microscope (TEM)
Application of focused ion beam milling to cross-sectional TEM specimen preparation of industrial materials including heterointerfaces, 92
Transmission electron microscopy
Transmission electron microscopy of thin-film transistors on glass substrates, 106
TEM observations of nanometer thick cobalt deposits in alumina sandwiches, 120
Cross-sectional TEM observation of multilayer structure of a galvannealed steel, 132
Transmission electron microscopy investigation of the structural characteristics of amorphous tetrahedral carbon films, 144
Twinning
Nanocrystalline thin titanium films grown on potassium bromide single crystals, 140

Vacuum arc deposition
Stable and metastable phases in the vacuum arc deposited Co thin films, 124
Volume expansion
The volume expansion of the $\{11\bar{2}0\}$ planar defect in 2H–GaN/6H–SiC $(0001)_{Si}$ grown by MBE, 153

Well layer
HR XRD for the analysis of ultrathin centrosymmetric strained DB-RTD heterostructures, 25

X-ray diffraction
New X-ray diffraction method for materials science, 16
Combined high resolution X-ray diffraction and EXAFS studies of $Si_{(1-x)}Ge_x$ heterostructures, 20
X-ray scattering study of quantum wires and lateral periodic heterostructures, 49
Structure characterization of metallic multilayers by symmetric and asymmetric X-ray diffraction, 78
Investigation of chemical ordering in MBE-grown Co_xPt_{1-x} films by X-ray diffraction and high-resolution transmission electron microscopy, 191
X-ray diffraction spectra
Fine interference effects in X-ray diffraction from multilayered structures, 35
X-ray reflectometry
Determination of interfacial roughness and its correlation in sputtered CoZr/Cu multilayers, 187

$YBa_2Cu_3O_{7-x}$ thin films
Epitaxial growth of $YBa_2Cu_3O_{7-x}$ thin films on (111) $SrTiO_3$ substrates, 202

ZrO_2
XRD and TEM study of heteroepitaxial growth of zirconia on magnesia single crystal, 197